Abstracts

Determination of Complex Dielectric and Magnetic Properties of Materials

S. Weisbrod, L.A. Morgan and L.R. Hughes. "Determination of Complex Dielectric and Magnetic Properties of Materials." 1977 MTT-S International Microwave Symposium Digest 77.1 (1977 [MWSYM]): 121-123.

The paper describes a modified Von Hippel technique for determination of complex dielectric and magnetic properties of materials. The technique uses least square fit to derive the scatter matrix parameters for calibrating out internal reflection between the sample and the reflection measuring equipment. Least square fit is also used to determine best values of µ and epsilon.

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